



Welcome to [E-XFL.COM](#)

Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

| | |
|---------------------------------|---|
| Product Status | Obsolete |
| Core Processor | MPC8xx |
| Number of Cores/Bus Width | 1 Core, 32-Bit |
| Speed | 50MHz |
| Co-Processors/DSP | Communications; CPM |
| RAM Controllers | DRAM |
| Graphics Acceleration | No |
| Display & Interface Controllers | - |
| Ethernet | 10Mbps (1), 10/100Mbps (1) |
| SATA | - |
| USB | - |
| Voltage - I/O | 3.3V |
| Operating Temperature | 0°C ~ 95°C (TA) |
| Security Features | - |
| Package / Case | 357-BBGA |
| Supplier Device Package | 357-PBGA (25x25) |
| Purchase URL | https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc855tzq50d4r2 |

2 Features

The following list summarizes the key MPC860 features:

- Embedded single-issue, 32-bit core (implementing the Power Architecture technology) with thirty-two 32-bit general-purpose registers (GPRs)
 - The core performs branch prediction with conditional prefetch without conditional execution.
 - 4- or 8-Kbyte data cache and 4- or 16-Kbyte instruction cache (see [Table 1](#))
 - 16-Kbyte instruction caches are four-way, set-associative with 256 sets; 4-Kbyte instruction caches are two-way, set-associative with 128 sets.
 - 8-Kbyte data caches are two-way, set-associative with 256 sets; 4-Kbyte data caches are two-way, set-associative with 128 sets.
 - Cache coherency for both instruction and data caches is maintained on 128-bit (4-word) cache blocks.
 - Caches are physically addressed, implement a least recently used (LRU) replacement algorithm, and are lockable on a cache block basis.
 - MMUs with 32-entry TLB, fully-associative instruction, and data TLBs
 - MMUs support multiple page sizes of 4-, 16-, and 512-Kbytes, and 8-Mbytes; 16 virtual address spaces and 16 protection groups
 - Advanced on-chip-emulation debug mode
- Up to 32-bit data bus (dynamic bus sizing for 8, 16, and 32 bits)
- 32 address lines
- Operates at up to 80 MHz
- Memory controller (eight banks)
 - Contains complete dynamic RAM (DRAM) controller
 - Each bank can be a chip select or $\overline{\text{RAS}}$ to support a DRAM bank.
 - Up to 15 wait states programmable per memory bank
 - Glueless interface to DRAM, SIMMS, SRAM, EPROM, Flash EPROM, and other memory devices
 - DRAM controller programmable to support most size and speed memory interfaces
 - Four $\overline{\text{CAS}}$ lines, four $\overline{\text{WE}}$ lines, and one $\overline{\text{OE}}$ line
 - Boot chip-select available at reset (options for 8-, 16-, or 32-bit memory)
 - Variable block sizes (32 Kbytes to 256 Mbytes)
 - Selectable write protection
 - On-chip bus arbitration logic
- General-purpose timers
 - Four 16-bit timers or two 32-bit timers
 - Gate mode can enable/disable counting
 - Interrupt can be masked on reference match and event capture.

Features

- Allows dynamic changes
- Can be internally connected to six serial channels (four SCCs and two SMCs)
- Parallel interface port (PIP)
 - Centronics interface support
 - Supports fast connection between compatible ports on the MPC860 or the MC68360
- PCMCIA interface
 - Master (socket) interface, release 2.1 compliant
 - Supports two independent PCMCIA sockets
 - Supports eight memory or I/O windows
- Low power support
 - Full on—all units fully powered
 - Doze—core functional units disabled except time base decremter, PLL, memory controller, RTC, and CPM in low-power standby
 - Sleep—all units disabled except RTC and PIT, PLL active for fast wake up
 - Deep sleep—all units disabled including PLL except RTC and PIT
 - Power down mode—all units powered down except PLL, RTC, PIT, time base, and decremter
- Debug interface
 - Eight comparators: four operate on instruction address, two operate on data address, and two operate on data
 - Supports conditions: = ≠ < >
 - Each watchpoint can generate a break-point internally.
- 3.3-V operation with 5-V TTL compatibility except EXTAL and EXTCLK
- 357-pin ball grid array (BGA) package

Figure 1 shows the undershoot and overshoot voltages at the interface of the MPC860.

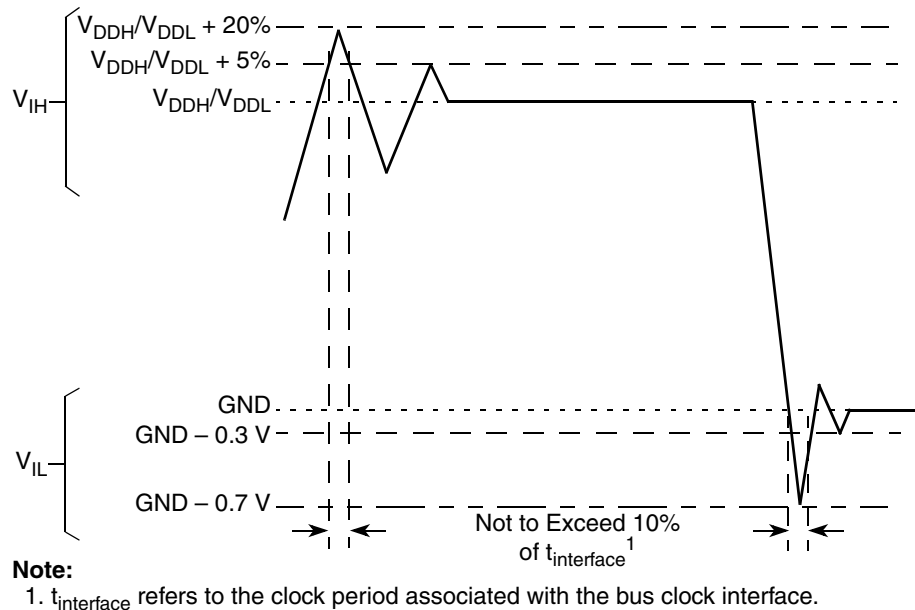


Figure 1. Undershoot/Overshoot Voltage for V_{DDH} and V_{DDL}

4 Thermal Characteristics

Table 3. Package Description

| Package Designator | Package Code (Case No.) | Package Description |
|--------------------|-------------------------|-------------------------|
| ZP | 5050 (1103-01) | PBGA 357 25*25*0.9P1.27 |
| ZQ/VR | 5058 (1103D-02) | PBGA 357 25*25*1.2P1.27 |

Table 6. DC Electrical Specifications (continued)

| Characteristic | Symbol | Min | Max | Unit |
|--|----------|-----|-----|---------------|
| Input leakage current, $V_{in} = 3.6\text{ V}$ (except TMS, $\overline{\text{TRST}}$, DSCK, and DSDI pins) | I_{In} | — | 10 | μA |
| Input leakage current, $V_{in} = 0\text{ V}$ (except TMS, $\overline{\text{TRST}}$, DSCK, and DSDI pins) | I_{In} | — | 10 | μA |
| Input capacitance ² | C_{in} | — | 20 | pF |
| Output high voltage, $I_{OH} = -2.0\text{ mA}$, $V_{DDH} = 3.0\text{ V}$ (except XTAL, XFC, and open-drain pins) | V_{OH} | 2.4 | — | V |
| Output low voltage $I_{OL} = 2.0\text{ mA}$, CLKOUT $I_{OL} = 3.2\text{ mA}$ ³ $I_{OL} = 5.3\text{ mA}$ ⁴ $I_{OL} = 7.0\text{ mA}$, TXD1/PA14, TXD2/PA12 $I_{OL} = 8.9\text{ mA}$, $\overline{\text{TS}}$, $\overline{\text{TA}}$, $\overline{\text{TEA}}$, $\overline{\text{BI}}$, $\overline{\text{BB}}$, $\overline{\text{HRESET}}$, $\overline{\text{SRESET}}$ | V_{OL} | — | 0.5 | V |

¹ $V_{IL}(\text{max})$ for the I²C interface is 0.8 V rather than the 1.5 V as specified in the I²C standard.

² Input capacitance is periodically sampled.

³ A(0:31), TSIZ0/ $\overline{\text{REG}}$, TSIZ1, D(0:31), DP(0:3)/ $\overline{\text{IRQ}}(3:6)$, RD/ $\overline{\text{WR}}$, $\overline{\text{BURST}}$, $\overline{\text{RSV}}/\overline{\text{IRQ2}}$, IP_B(0:1)/IWP(0:1)/VFLS(0:1), IP_B2/IOIS16_B/AT2, IP_B3/IWP2/VF2, IP_B4/LWP0/VF0, IP_B5/LWP1/VF1, IP_B6/DSDI/AT0, IP_B7/PTR/AT3, RXD1/PA15, RXD2/PA13, L1TXDB/PA11, L1RXDB/PA10, L1TXDA/PA9, L1RXDA/PA8, TIN1/L1RCLKA/BRGO1/CLK1/PA7, BRGCLK1/ $\overline{\text{TOUT1}}/\text{CLK2}/\text{PA6}$, TIN2/L1TCLKA/BRGO2/CLK3/PA5, $\overline{\text{TOUT2}}/\text{CLK4}/\text{PA4}$, TIN3/BRGO3/CLK5/PA3, BRGCLK2/L1RCLKB/ $\overline{\text{TOUT3}}/\text{CLK6}/\text{PA2}$, TIN4/BRGO4/CLK7/PA1, L1TCLKB/ $\overline{\text{TOUT4}}/\text{CLK8}/\text{PA0}$, $\overline{\text{REJCT1}}/\text{SPISEL}/\text{PB31}$, SPICLK/PB30, SPIMOSI/PB29, BRGO4/SPIMISO/PB28, BRGO1/I2CSDA/PB27, BRGO2/I2CSCL/PB26, SMTXD1/PB25, SMRXD1/PB24, $\overline{\text{SMSYN1}}/\overline{\text{SDACK1}}/\text{PB23}$, $\overline{\text{SMSYN2}}/\overline{\text{SDACK2}}/\text{PB22}$, SMTXD2/L1CLKOB/PB21, SMRXD2/L1CLKOA/PB20, L1ST1/ $\overline{\text{RTS1}}/\text{PB19}$, L1ST2/ $\overline{\text{RTS2}}/\text{PB18}$, L1ST3/L1RQB/PB17, L1ST4/L1RQA/PB16, BRGO3/PB15, $\overline{\text{RSTRT1}}/\text{PB14}$, L1ST1/ $\overline{\text{RTS1}}/\overline{\text{DREQ0}}/\text{PC15}$, L1ST2/ $\overline{\text{RTS2}}/\overline{\text{DREQ1}}/\text{PC14}$, L1ST3/L1RQB/PC13, L1ST4/L1RQA/PC12, $\overline{\text{CTS1}}/\text{PC11}$, $\overline{\text{TGATE1}}/\overline{\text{CD1}}/\text{PC10}$, $\overline{\text{CTS2}}/\text{PC9}$, $\overline{\text{TGATE2}}/\overline{\text{CD2}}/\text{PC8}$, $\overline{\text{SDACK2}}/\text{L1TSYNCA}/\text{PC7}$, L1RSYNCA/PC6, $\overline{\text{SDACK1}}/\text{L1TSYNCA}/\text{PC5}$, L1RSYNCA/PC4, PD15, PD14, PD13, PD12, PD11, PD10, PD9, PD8, PD5, PD6, PD7, PD4, PD3, MII_MDC, MII_TX_ER, MII_EN, MII_MDIO, and MII_TXD[0:3]

⁴ $\overline{\text{BDIP}}/\overline{\text{GPL}}_B(5)$, $\overline{\text{BR}}$, $\overline{\text{BG}}$, $\overline{\text{FRZ}}/\overline{\text{IRQ6}}$, $\overline{\text{CS}}(0:5)$, $\overline{\text{CS}}(6)/\overline{\text{CE}}(1)_B$, $\overline{\text{CS}}(7)/\overline{\text{CE}}(2)_B$, $\overline{\text{WE0}}/\overline{\text{BS}}_B0/\overline{\text{IORD}}$, $\overline{\text{WE1}}/\overline{\text{BS}}_B1/\overline{\text{IOWR}}$, $\overline{\text{WE2}}/\overline{\text{BS}}_B2/\overline{\text{PCOE}}$, $\overline{\text{WE3}}/\overline{\text{BS}}_B3/\overline{\text{PCWE}}$, $\overline{\text{BS}}_A(0:3)$, $\overline{\text{GPL}}_A0/\overline{\text{GPL}}_B0$, $\overline{\text{OE}}/\overline{\text{GPL}}_A1/\overline{\text{GPL}}_B1$, $\overline{\text{GPL}}_A(2:3)/\overline{\text{GPL}}_B(2:3)/\overline{\text{CS}}(2:3)$, UPWAITA/ $\overline{\text{GPL}}_A4$, UPWAITB/ $\overline{\text{GPL}}_B4$, $\overline{\text{GPL}}_A5$, ALE_A, $\overline{\text{CE1}}_A$, $\overline{\text{CE2}}_A$, ALE_B/DSCK/AT1, OP(0:1), OP2/MODCK1/ $\overline{\text{STS}}$, OP3/MODCK2/DSDO, and BADDR(28:30)

7 Thermal Calculation and Measurement

For the following discussions, $P_D = (V_{DD} \times I_{DD}) + P_{I/O}$, where $P_{I/O}$ is the power dissipation of the I/O drivers.

7.1 Estimation with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_J , in °C can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_A = ambient temperature (°C)

$R_{\theta JA}$ = package junction-to-ambient thermal resistance (°C/W)

P_D = power dissipation in package

The junction-to-ambient thermal resistance is an industry standard value which provides a quick and easy estimation of thermal performance. However, the answer is only an estimate; test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

7.2 Estimation with Junction-to-Case Thermal Resistance

Historically, the thermal resistance has frequently been expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

$R_{\theta JC}$ = junction-to-case thermal resistance (°C/W)

$R_{\theta CA}$ = case-to-ambient thermal resistance (°C/W)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user adjusts the thermal environment to affect the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the airflow around the device, add a heat sink, change the mounting arrangement on the printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device. This thermal model is most useful for ceramic packages with heat sinks where some 90% of the heat flows through the case and the heat sink to the ambient environment. For most packages, a better model is required.

7.3 Estimation with Junction-to-Board Thermal Resistance

A simple package thermal model which has demonstrated reasonable accuracy (about 20%) is a two-resistor model consisting of a junction-to-board and a junction-to-case thermal resistance. The junction-to-case thermal resistance covers the situation where a heat sink is used or where a substantial amount of heat is dissipated from the top of the package. The junction-to-board thermal resistance describes the thermal performance when most of the heat is conducted to the printed-circuit board. It has been observed that the thermal performance of most plastic packages, especially PBGA packages, is strongly dependent on the board temperature; see [Figure 2](#).

Table 7. Bus Operation Timings (continued)

| Num | Characteristic | 33 MHz | | 40 MHz | | 50 MHz | | 66 MHz | | Unit |
|------|---|--------|------|--------|------|--------|------|--------|------|------|
| | | Min | Max | Min | Max | Min | Max | Min | Max | |
| B29d | $\overline{WE}(0:3)$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 0 | 43.45 | — | 35.5 | — | 28.00 | — | 20.73 | — | ns |
| B29e | \overline{CS} negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0 | 43.45 | — | 35.5 | — | 28.00 | — | 29.73 | — | ns |
| B29f | $\overline{WE}(0:3)$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, EBDF = 1 | 8.86 | — | 6.88 | — | 5.00 | — | 3.18 | — | ns |
| B29g | \overline{CS} negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1 | 8.86 | — | 6.88 | — | 5.00 | — | 3.18 | — | ns |
| B29h | $\overline{WE}(0:3)$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 1 | 38.67 | — | 31.38 | — | 24.50 | — | 17.83 | — | ns |
| B29i | \overline{CS} negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1 | 38.67 | — | 31.38 | — | 24.50 | — | 17.83 | — | ns |
| B30 | \overline{CS} , $\overline{WE}(0:3)$ negated to A(0:31), BADDR(28:30) invalid GPCM write access ⁸ | 5.58 | — | 4.25 | — | 3.00 | — | 1.79 | — | ns |
| B30a | $\overline{WE}(0:3)$ negated to A(0:31), BADDR(28:30) invalid GPCM, write access, TRLX = 0, CSNT = 1, \overline{CS} negated to A(0:31) invalid GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0 | 13.15 | — | 10.50 | — | 8.00 | — | 5.58 | — | ns |
| B30b | $\overline{WE}(0:3)$ negated to A(0:31), invalid GPCM BADDR(28:30) invalid GPCM write access, TRLX = 1, CSNT = 1. \overline{CS} negated to A(0:31), Invalid GPCM, write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0 | 43.45 | — | 35.50 | — | 28.00 | — | 20.73 | — | ns |
| B30c | $\overline{WE}(0:3)$ negated to A(0:31), BADDR(28:30) invalid GPCM write access, TRLX = 0, CSNT = 1. \overline{CS} negated to A(0:31) invalid GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, ACS = 11, EBDF = 1 | 8.36 | — | 6.38 | — | 4.50 | — | 2.68 | — | ns |
| B30d | $\overline{WE}(0:3)$ negated to A(0:31), BADDR(28:30) invalid GPCM write access, TRLX = 1, CSNT = 1. \overline{CS} negated to A(0:31) invalid GPCM write access TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1 | 38.67 | — | 31.38 | — | 24.50 | — | 17.83 | — | ns |
| B31 | CLKOUT falling edge to \overline{CS} valid—as requested by control bit CST4 in the corresponding word in UPM | 1.50 | 6.00 | 1.50 | 6.00 | 1.50 | 6.00 | 1.50 | 6.00 | ns |

Figure 9 provides the timing for the input data controlled by the UPM for data beats where $DLT3 = 1$ in the UPM RAM words. (This is only the case where data is latched on the falling edge of CLKOUT.)

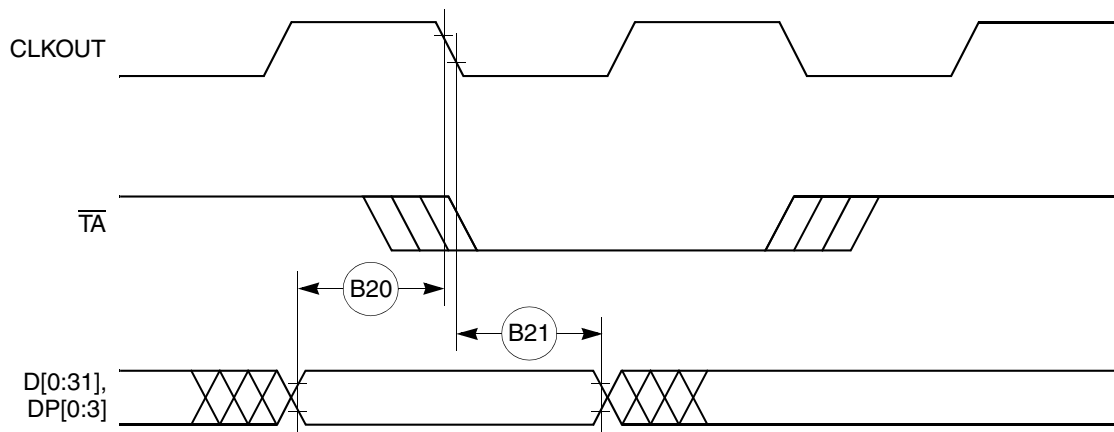


Figure 9. Input Data Timing when Controlled by UPM in the Memory Controller and $DLT3 = 1$

Figure 10 through Figure 13 provide the timing for the external bus read controlled by various GPCM factors.

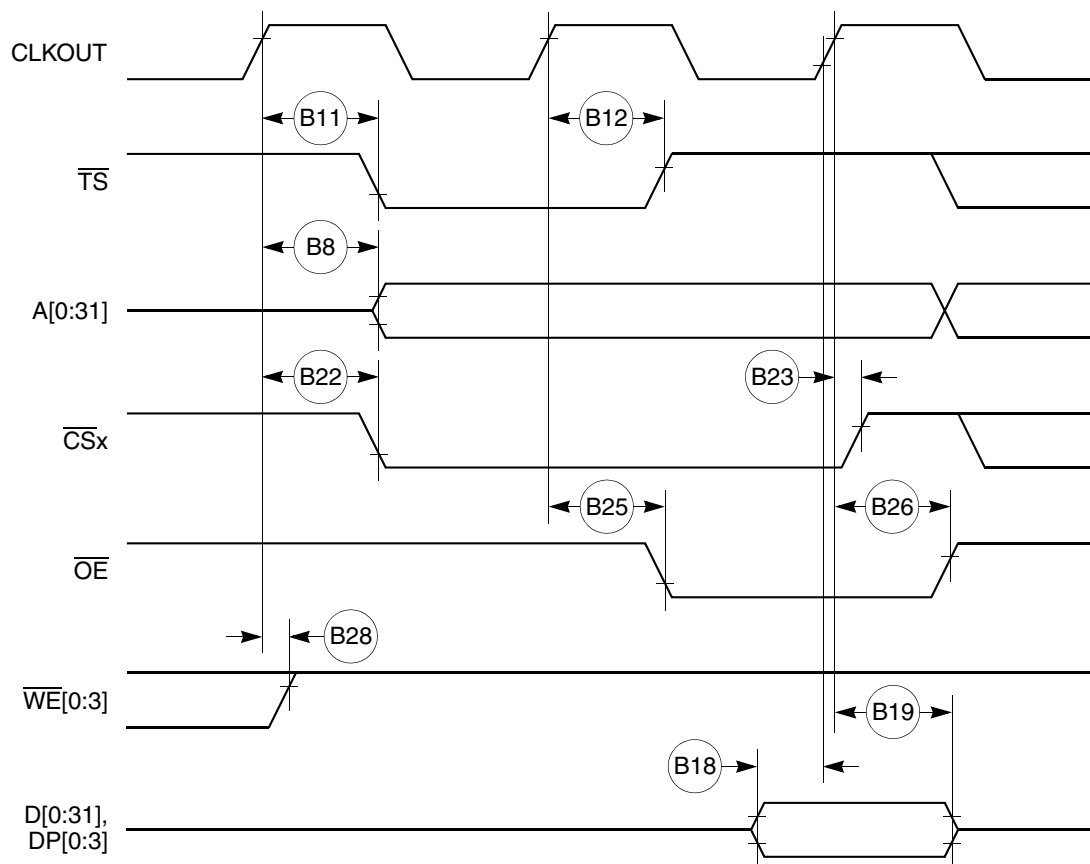


Figure 10. External Bus Read Timing (GPCM Controlled— $ACS = 00$)

Figure 20 provides the timing for the synchronous external master access controlled by the GPCM.

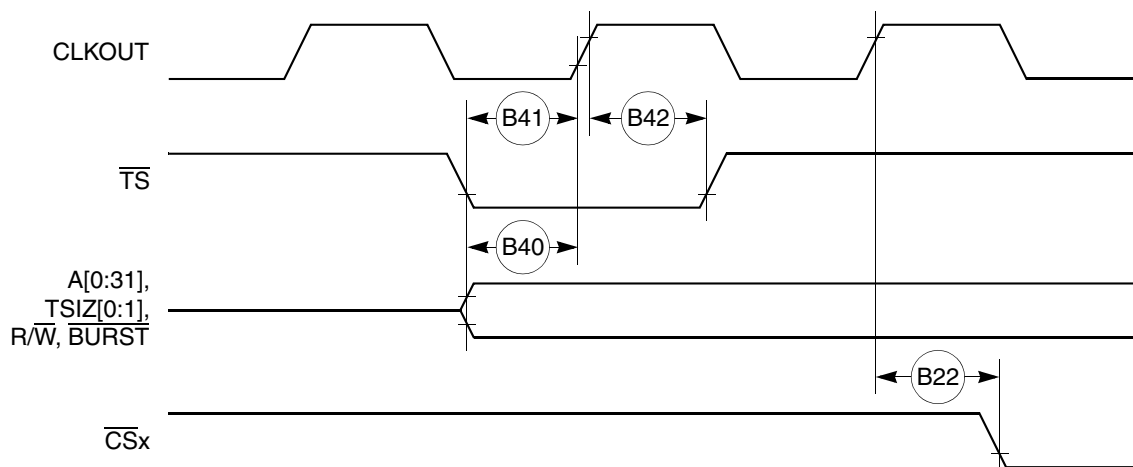


Figure 20. Synchronous External Master Access Timing (GPCM Handled ACS = 00)

Figure 21 provides the timing for the asynchronous external master memory access controlled by the GPCM.

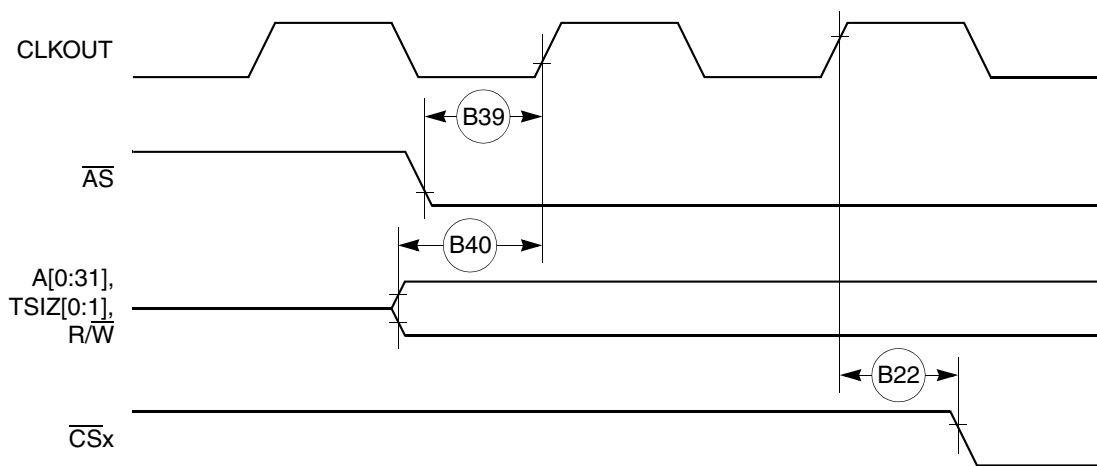


Figure 21. Asynchronous External Master Memory Access Timing (GPCM Controlled—ACS = 00)

Figure 22 provides the timing for the asynchronous external master control signals negation.

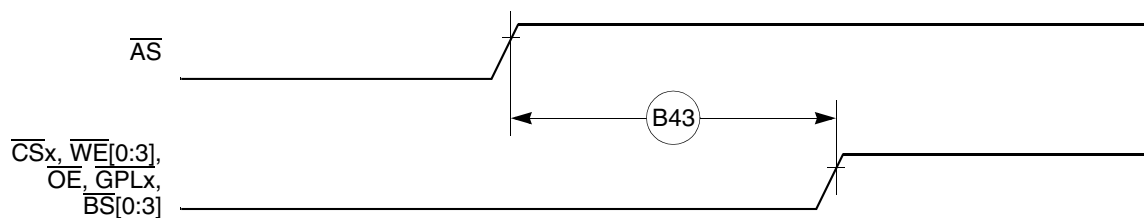


Figure 22. Asynchronous External Master—Control Signals Negation Timing

Table 8 provides interrupt timing for the MPC860.

Table 8. Interrupt Timing

| Num | Characteristic ¹ | All Frequencies | | Unit |
|-----|--|--------------------------------|-----|------|
| | | Min | Max | |
| I39 | $\overline{\text{IRQ}}_x$ valid to CLKOUT rising edge (setup time) | 6.00 | — | ns |
| I40 | $\overline{\text{IRQ}}_x$ hold time after CLKOUT | 2.00 | — | ns |
| I41 | $\overline{\text{IRQ}}_x$ pulse width low | 3.00 | — | ns |
| I42 | $\overline{\text{IRQ}}_x$ pulse width high | 3.00 | — | ns |
| I43 | $\overline{\text{IRQ}}_x$ edge-to-edge time | $4 \times T_{\text{CLOCKOUT}}$ | — | — |

¹ The timings I39 and I40 describe the testing conditions under which the $\overline{\text{IRQ}}$ lines are tested when being defined as level-sensitive. The $\overline{\text{IRQ}}$ lines are synchronized internally and do not have to be asserted or negated with reference to the CLKOUT.
The timings I41, I42, and I43 are specified to allow the correct function of the $\overline{\text{IRQ}}$ lines detection circuitry and have no direct relation with the total system interrupt latency that the MPC860 is able to support.

Figure 23 provides the interrupt detection timing for the external level-sensitive lines.

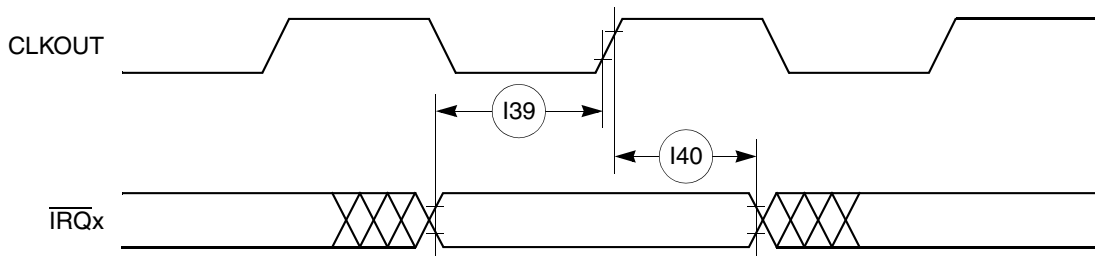


Figure 23. Interrupt Detection Timing for External Level Sensitive Lines

Figure 24 provides the interrupt detection timing for the external edge-sensitive lines.

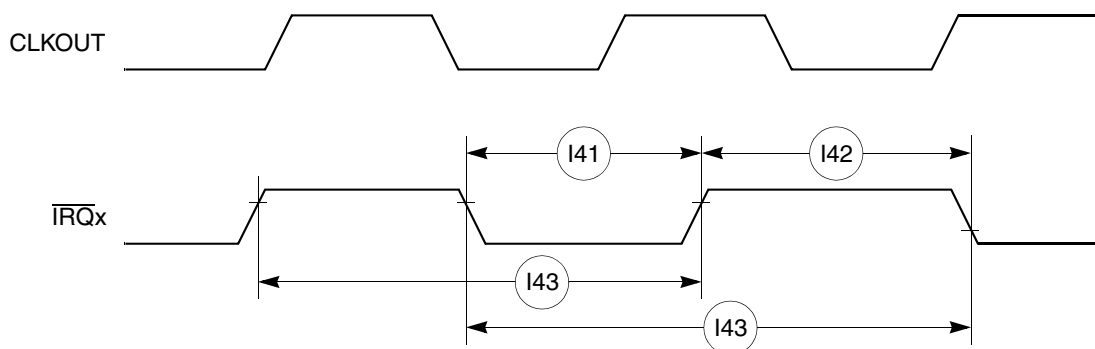


Figure 24. Interrupt Detection Timing for External Edge Sensitive Lines

Figure 25 provides the PCMCIA access cycle timing for the external bus read.

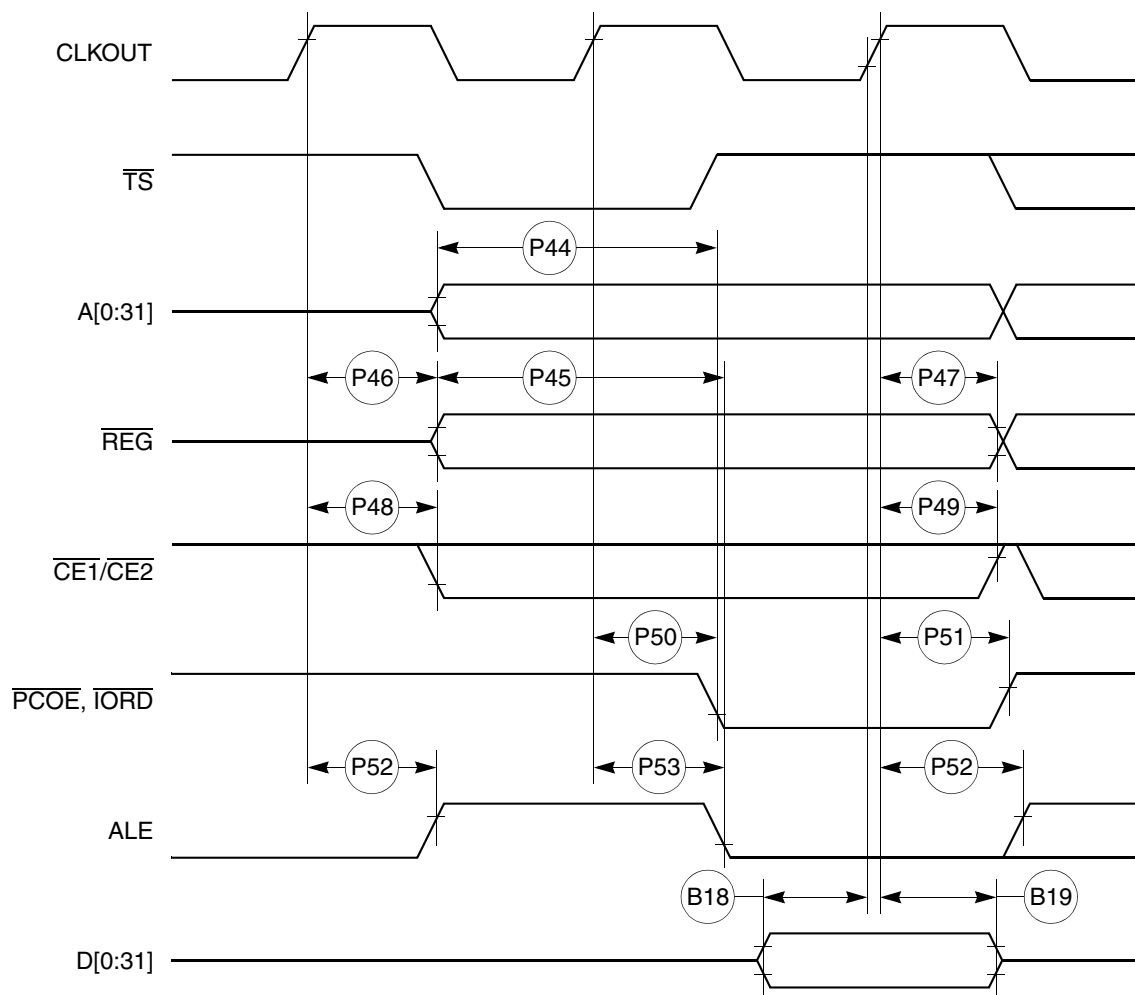


Figure 25. PCMCIA Access Cycle Timing External Bus Read

Table 11 shows the debug port timing for the MPC860.

Table 11. Debug Port Timing

| Num | Characteristic | All Frequencies | | Unit |
|-----|-----------------------------|-----------------------------------|-------|------|
| | | Min | Max | |
| P61 | DSCK cycle time | $3 \times T_{\text{CLOCKOUT}}$ | — | — |
| P62 | DSCK clock pulse width | $1.25 \times T_{\text{CLOCKOUT}}$ | — | — |
| P63 | DSCK rise and fall times | 0.00 | 3.00 | ns |
| P64 | DSDI input data setup time | 8.00 | — | ns |
| P65 | DSDI data hold time | 5.00 | — | ns |
| P66 | DSCK low to DSDO data valid | 0.00 | 15.00 | ns |
| P67 | DSCK low to DSDO invalid | 0.00 | 2.00 | ns |

Figure 30 provides the input timing for the debug port clock.

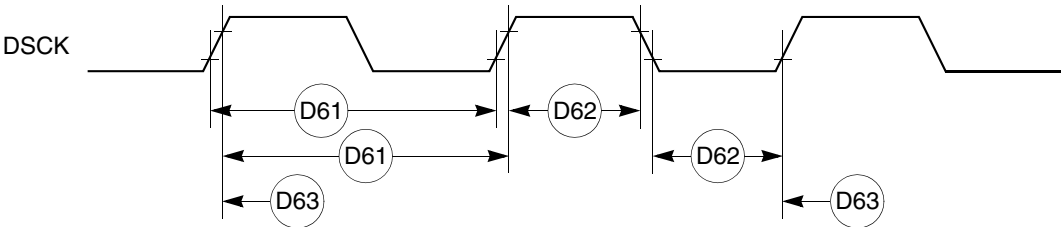


Figure 30. Debug Port Clock Input Timing

Figure 31 provides the timing for the debug port.

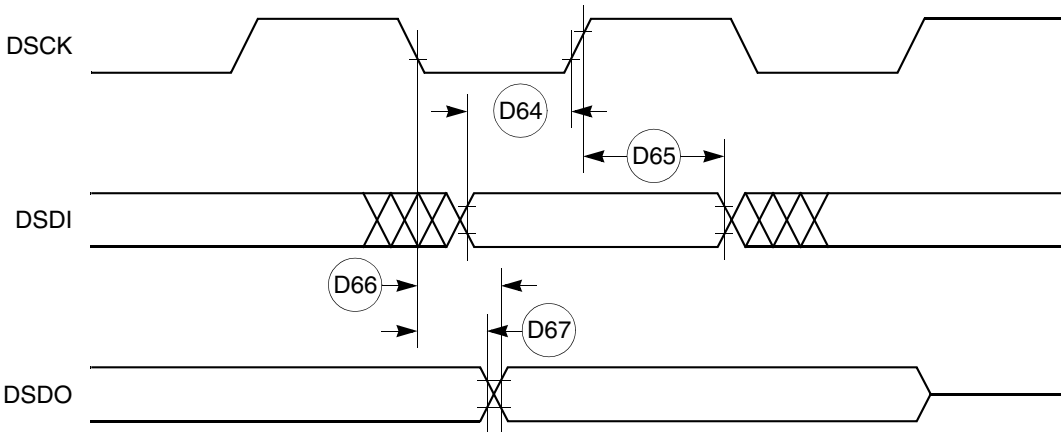


Figure 31. Debug Port Timings

Figure 34 provides the reset timing for the debug port configuration.

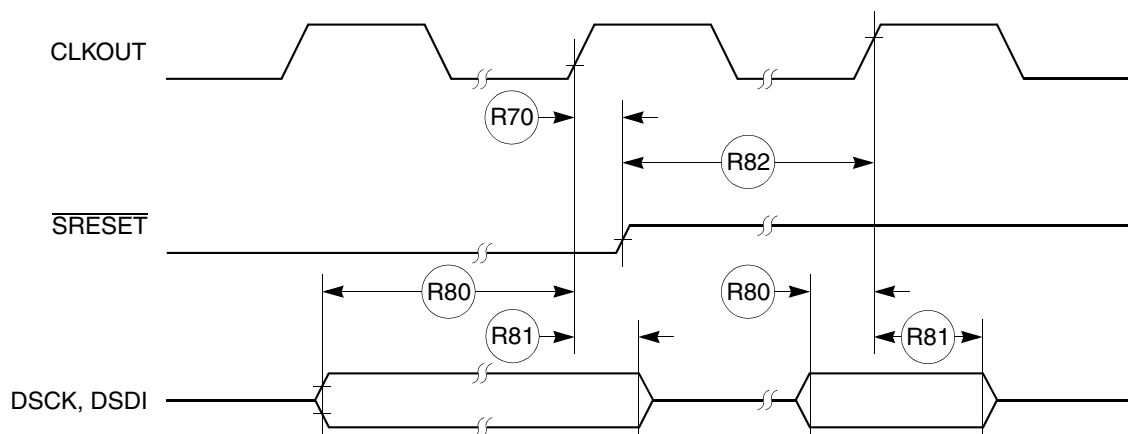


Figure 34. Reset Timing—Debug Port Configuration

10 IEEE 1149.1 Electrical Specifications

Table 13 provides the JTAG timings for the MPC860 shown in Figure 35 through Figure 38.

Table 13. JTAG Timing

| Num | Characteristic | All Frequencies | | Unit |
|-----|--|-----------------|-------|------|
| | | Min | Max | |
| J82 | TCK cycle time | 100.00 | — | ns |
| J83 | TCK clock pulse width measured at 1.5 V | 40.00 | — | ns |
| J84 | TCK rise and fall times | 0.00 | 10.00 | ns |
| J85 | TMS, TDI data setup time | 5.00 | — | ns |
| J86 | TMS, TDI data hold time | 25.00 | — | ns |
| J87 | TCK low to TDO data valid | — | 27.00 | ns |
| J88 | TCK low to TDO data invalid | 0.00 | — | ns |
| J89 | TCK low to TDO high impedance | — | 20.00 | ns |
| J90 | $\overline{\text{TRST}}$ assert time | 100.00 | — | ns |
| J91 | $\overline{\text{TRST}}$ setup time to TCK low | 40.00 | — | ns |
| J92 | TCK falling edge to output valid | — | 50.00 | ns |
| J93 | TCK falling edge to output valid out of high impedance | — | 50.00 | ns |
| J94 | TCK falling edge to output high impedance | — | 50.00 | ns |
| J95 | Boundary scan input valid to TCK rising edge | 50.00 | — | ns |
| J96 | TCK rising edge to boundary scan input invalid | 50.00 | — | ns |

11 CPM Electrical Characteristics

This section provides the AC and DC electrical specifications for the communications processor module (CPM) of the MPC860.

11.1 PIP/PIO AC Electrical Specifications

Table 14 provides the PIP/PIO AC timings as shown in Figure 39 through Figure 43.

Table 14. PIP/PIO Timing

| Num | Characteristic | All Frequencies | | Unit |
|-----|--|-----------------|-----|------|
| | | Min | Max | |
| 21 | Data-in setup time to STBI low | 0 | — | ns |
| 22 | Data-in hold time to STBI high | $2.5 - t_3^1$ | — | CLK |
| 23 | STBI pulse width | 1.5 | — | CLK |
| 24 | STBO pulse width | 1 CLK – 5 ns | — | ns |
| 25 | Data-out setup time to STBO low | 2 | — | CLK |
| 26 | Data-out hold time from STBO high | 5 | — | CLK |
| 27 | STBI low to STBO low (Rx interlock) | — | 2 | CLK |
| 28 | STBI low to STBO high (Tx interlock) | 2 | — | CLK |
| 29 | Data-in setup time to clock high | 15 | — | ns |
| 30 | Data-in hold time from clock high | 7.5 | — | ns |
| 31 | Clock low to data-out valid (CPU writes data, control, or direction) | — | 25 | ns |

¹ t_3 = Specification 23.

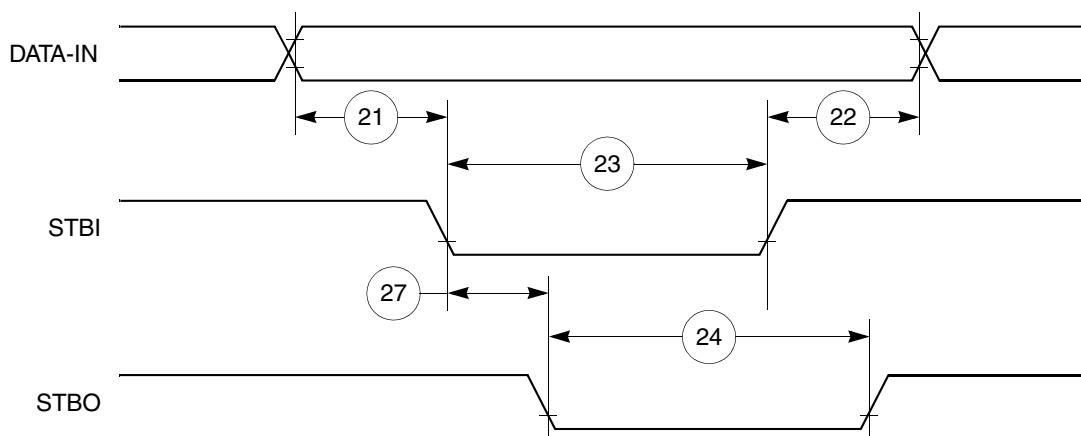


Figure 39. PIP Rx (Interlock Mode) Timing Diagram

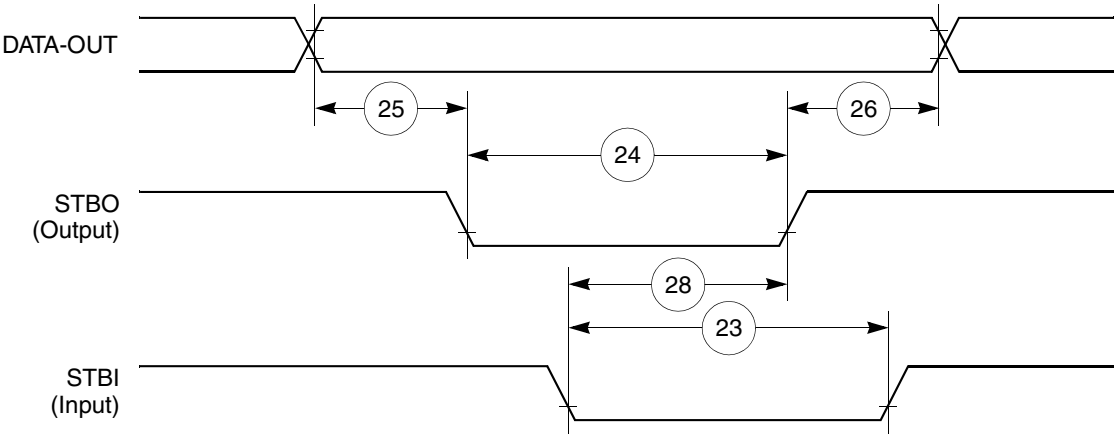


Figure 40. PIP Tx (Interlock Mode) Timing Diagram

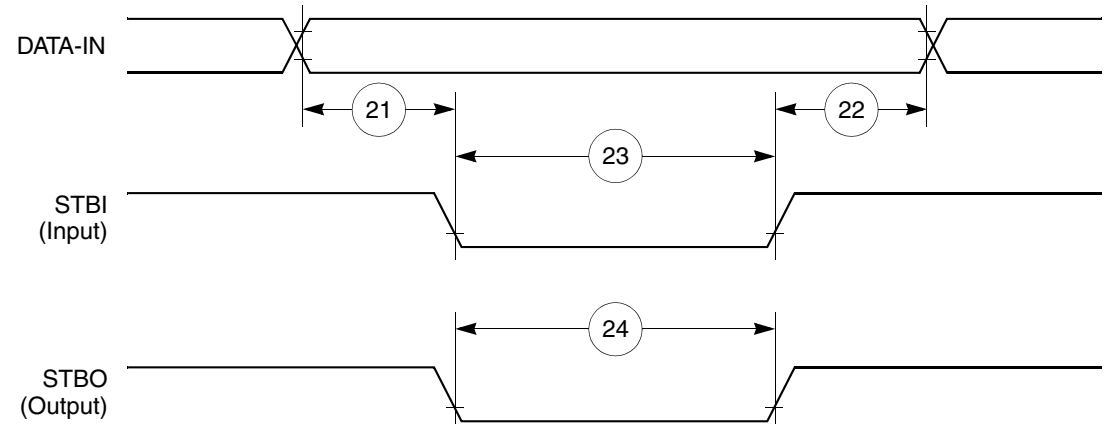


Figure 41. PIP Rx (Pulse Mode) Timing Diagram

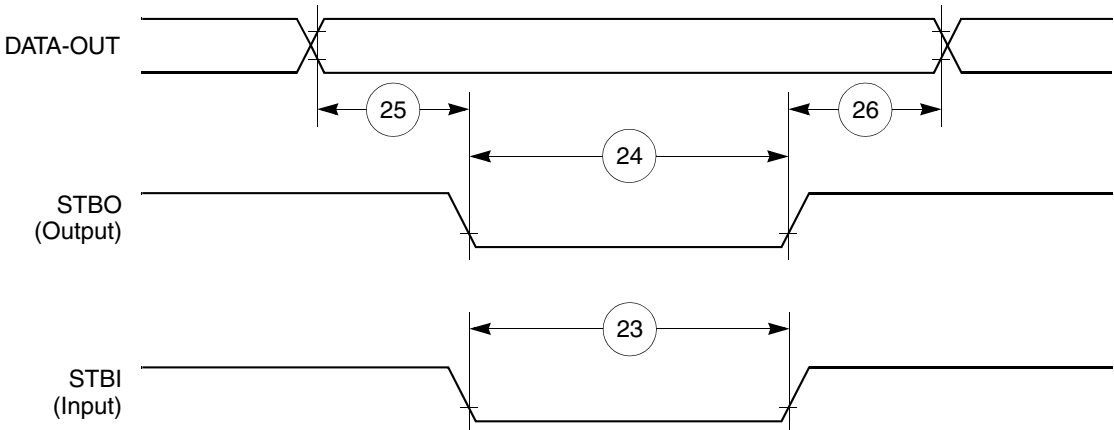


Figure 42. PIP TX (Pulse Mode) Timing Diagram

11.7 SCC in NMSI Mode Electrical Specifications

Table 20 provides the NMSI external clock timing.

Table 20. NMSI External Clock Timing

| Num | Characteristic | All Frequencies | | Unit |
|-----|--|-----------------|-------|------|
| | | Min | Max | |
| 100 | RCLK1 and TCLK1 width high ¹ | 1/SYNCCLK | — | ns |
| 101 | RCLK1 and TCLK1 width low | 1/SYNCCLK + 5 | — | ns |
| 102 | RCLK1 and TCLK1 rise/fall time | — | 15.00 | ns |
| 103 | TXD1 active delay (from TCLK1 falling edge) | 0.00 | 50.00 | ns |
| 104 | $\overline{\text{RTS1}}$ active/inactive delay (from TCLK1 falling edge) | 0.00 | 50.00 | ns |
| 105 | $\overline{\text{CTS1}}$ setup time to TCLK1 rising edge | 5.00 | — | ns |
| 106 | RXD1 setup time to RCLK1 rising edge | 5.00 | — | ns |
| 107 | RXD1 hold time from RCLK1 rising edge ² | 5.00 | — | ns |
| 108 | $\overline{\text{CD1}}$ setup Time to RCLK1 rising edge | 5.00 | — | ns |

¹ The ratios SYNCCLK/RCLK1 and SYNCCLK/TCLK1 must be greater than or equal to 2.25/1.

² Also applies to $\overline{\text{CD}}$ and $\overline{\text{CTS}}$ hold time when they are used as external sync signals.

Table 21 provides the NMSI internal clock timing.

Table 21. NMSI Internal Clock Timing

| Num | Characteristic | All Frequencies | | Unit |
|-----|--|-----------------|-----------|------|
| | | Min | Max | |
| 100 | RCLK1 and TCLK1 frequency ¹ | 0.00 | SYNCCLK/3 | MHz |
| 102 | RCLK1 and TCLK1 rise/fall time | — | — | ns |
| 103 | TXD1 active delay (from TCLK1 falling edge) | 0.00 | 30.00 | ns |
| 104 | $\overline{\text{RTS1}}$ active/inactive delay (from TCLK1 falling edge) | 0.00 | 30.00 | ns |
| 105 | $\overline{\text{CTS1}}$ setup time to TCLK1 rising edge | 40.00 | — | ns |
| 106 | RXD1 setup time to RCLK1 rising edge | 40.00 | — | ns |
| 107 | RXD1 hold time from RCLK1 rising edge ² | 0.00 | — | ns |
| 108 | $\overline{\text{CD1}}$ setup time to RCLK1 rising edge | 40.00 | — | ns |

¹ The ratios SYNCCLK/RCLK1 and SYNCCLK/TCLK1 must be greater than or equal to 3/1.

² Also applies to $\overline{\text{CD}}$ and $\overline{\text{CTS}}$ hold time when they are used as external sync signals.

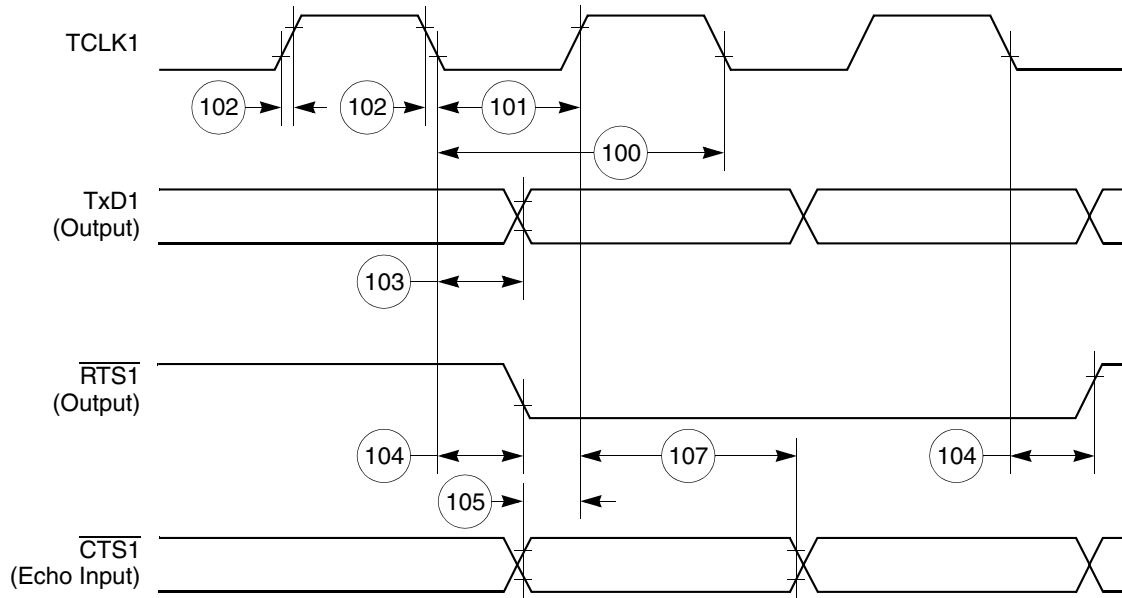


Figure 58. HDLC Bus Timing Diagram

11.8 Ethernet Electrical Specifications

Table 22 provides the Ethernet timings as shown in Figure 59 through Figure 63.

Table 22. Ethernet Timing

| Num | Characteristic | All Frequencies | | Unit |
|-----|---|-----------------|-----|------|
| | | Min | Max | |
| 120 | CLSN width high | 40 | — | ns |
| 121 | RCLK1 rise/fall time | — | 15 | ns |
| 122 | RCLK1 width low | 40 | — | ns |
| 123 | RCLK1 clock period ¹ | 80 | 120 | ns |
| 124 | RXD1 setup time | 20 | — | ns |
| 125 | RXD1 hold time | 5 | — | ns |
| 126 | RENA active delay (from RCLK1 rising edge of the last data bit) | 10 | — | ns |
| 127 | RENA width low | 100 | — | ns |
| 128 | TCLK1 rise/fall time | — | 15 | ns |
| 129 | TCLK1 width low | 40 | — | ns |
| 130 | TCLK1 clock period ¹ | 99 | 101 | ns |
| 131 | TXD1 active delay (from TCLK1 rising edge) | 10 | 50 | ns |
| 132 | TXD1 inactive delay (from TCLK1 rising edge) | 10 | 50 | ns |
| 133 | TENA active delay (from TCLK1 rising edge) | 10 | 50 | ns |
| 134 | TENA inactive delay (from TCLK1 rising edge) | 10 | 50 | ns |

Table 22. Ethernet Timing (continued)

| Num | Characteristic | All Frequencies | | Unit |
|-----|--|-----------------|-----|------|
| | | Min | Max | |
| 135 | $\overline{\text{RSTRT}}$ active delay (from TCLK1 falling edge) | 10 | 50 | ns |
| 136 | $\overline{\text{RSTRT}}$ inactive delay (from TCLK1 falling edge) | 10 | 50 | ns |
| 137 | $\overline{\text{REJECT}}$ width low | 1 | — | CLK |
| 138 | CLKO1 low to $\overline{\text{SDACK}}$ asserted ² | — | 20 | ns |
| 139 | CLKO1 low to $\overline{\text{SDACK}}$ negated ² | — | 20 | ns |

¹ The ratios SYNCCLK/RCLK1 and SYNCCLK/TCLK1 must be greater than or equal to 2/1.

² $\overline{\text{SDACK}}$ is asserted whenever the SDMA writes the incoming frame DA into memory.

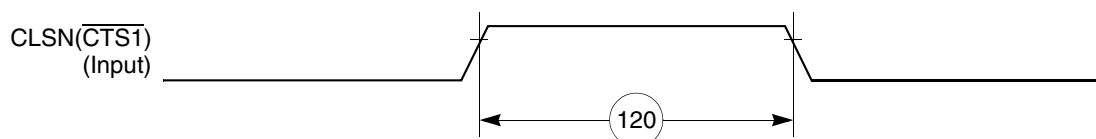


Figure 59. Ethernet Collision Timing Diagram

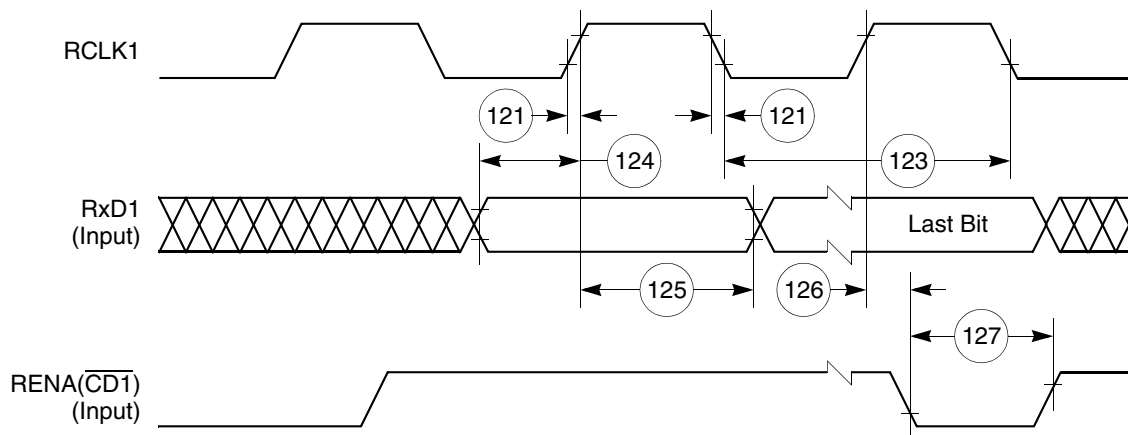


Figure 60. Ethernet Receive Timing Diagram

11.12 I²C AC Electrical Specifications

Table 26 provides the I²C (SCL < 100 kHz) timings.

Table 26. I²C Timing (SCL < 100 kHz)

| Num | Characteristic | All Frequencies | | Unit |
|-----|---|-----------------|-----|------|
| | | Min | Max | |
| 200 | SCL clock frequency (slave) | 0 | 100 | kHz |
| 200 | SCL clock frequency (master) ¹ | 1.5 | 100 | kHz |
| 202 | Bus free time between transmissions | 4.7 | — | μs |
| 203 | Low period of SCL | 4.7 | — | μs |
| 204 | High period of SCL | 4.0 | — | μs |
| 205 | Start condition setup time | 4.7 | — | μs |
| 206 | Start condition hold time | 4.0 | — | μs |
| 207 | Data hold time | 0 | — | μs |
| 208 | Data setup time | 250 | — | ns |
| 209 | SDL/SCL rise time | — | 1 | μs |
| 210 | SDL/SCL fall time | — | 300 | ns |
| 211 | Stop condition setup time | 4.7 | — | μs |

¹ SCL frequency is given by $SCL = BRGCLK_frequency / ((BRG\ register + 3) \times pre_scaler \times 2)$.
The ratio SYNCCLK/(BRGCLK/pre_scaler) must be greater than or equal to 4/1.

Table 27 provides the I²C (SCL > 100 kHz) timings.

Table 27. I²C Timing (SCL > 100 kHz)

| Num | Characteristic | Expression | All Frequencies | | Unit |
|-----|---|------------|-----------------|---------------|------|
| | | | Min | Max | |
| 200 | SCL clock frequency (slave) | fSCL | 0 | BRGCLK/48 | Hz |
| 200 | SCL clock frequency (master) ¹ | fSCL | BRGCLK/16512 | BRGCLK/48 | Hz |
| 202 | Bus free time between transmissions | | 1/(2.2 * fSCL) | — | s |
| 203 | Low period of SCL | | 1/(2.2 * fSCL) | — | s |
| 204 | High period of SCL | | 1/(2.2 * fSCL) | — | s |
| 205 | Start condition setup time | | 1/(2.2 * fSCL) | — | s |
| 206 | Start condition hold time | | 1/(2.2 * fSCL) | — | s |
| 207 | Data hold time | | 0 | — | s |
| 208 | Data setup time | | 1/(40 * fSCL) | — | s |
| 209 | SDL/SCL rise time | | — | 1/(10 * fSCL) | s |
| 210 | SDL/SCL fall time | | — | 1/(33 * fSCL) | s |
| 211 | Stop condition setup time | | 1/2(2.2 * fSCL) | — | s |

¹ SCL frequency is given by $SCL = BRGCLK_frequency / ((BRG\ register + 3) \times pre_scaler \times 2)$.
The ratio SYNCCLK/(BRGCLK / pre_scaler) must be greater than or equal to 4/1.

13.2 MII Transmit Signal Timing (MII_TXD[3:0], MII_TX_EN, MII_TX_ER, MII_TX_CLK)

The transmitter functions correctly up to a MII_TX_CLK maximum frequency of 25 MHz +1%. There is no minimum frequency requirement. In addition, the processor clock frequency must exceed the MII_TX_CLK frequency – 1%.

Table 30 provides information on the MII transmit signal timing.

Table 30. MII Transmit Signal Timing

| Num | Characteristic | Min | Max | Unit |
|-----|--|-----|-----|-------------------|
| M5 | MII_TX_CLK to MII_TXD[3:0], MII_TX_EN, MII_TX_ER invalid | 5 | — | ns |
| M6 | MII_TX_CLK to MII_TXD[3:0], MII_TX_EN, MII_TX_ER valid | — | 25 | |
| M7 | MII_TX_CLK pulse width high | 35 | 65% | MII_TX_CLK period |
| M8 | MII_TX_CLK pulse width low | 35% | 65% | MII_TX_CLK period |

Figure 73 shows the MII transmit signal timing diagram.

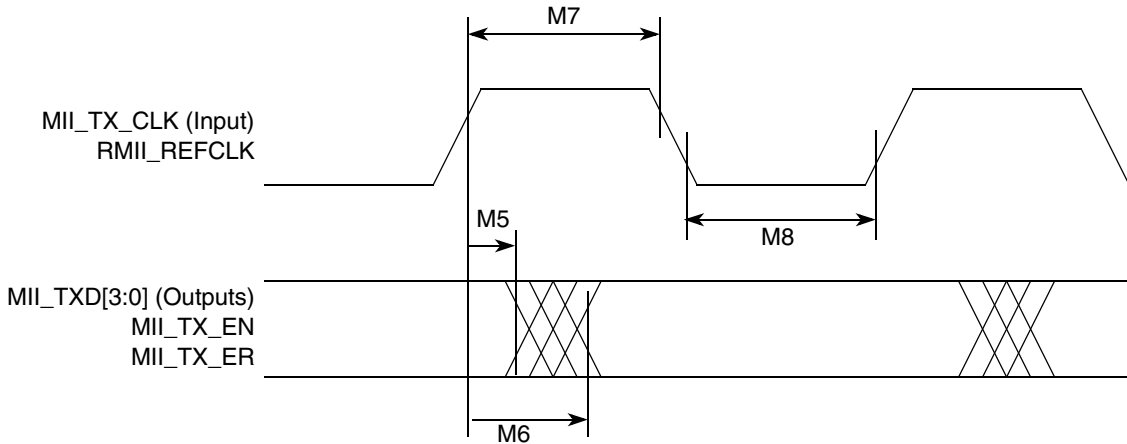


Figure 73. MII Transmit Signal Timing Diagram

15 Document Revision History

Table 35 lists significant changes between revisions of this hardware specification.

Table 35. Document Revision History

| Revision | Date | Changes |
|----------|---------|--|
| 10 | 09/2015 | In Table 34 , moved MPC855TCVR50D4 and MPC855TCVR66D4 under the extended temperature (–40° to 95°C) and removed MC860ENCVR50D4R2 from the normal temperature Tape and Reel. |
| 9 | 10/2011 | Updated orderable part numbers in Table 34 , “MPC860 Family Package/Frequency Availability.” |
| 8 | 08/2007 | <ul style="list-style-type: none"> Updated template. On page 1, added a second paragraph. After Table 2, inserted a new figure showing the undershoot/overshoot voltage (Figure 1) and renumbered the rest of the figures. In Figure 3, changed all reference voltage measurement points from 0.2 and 0.8 V to 50% level. In Table 16, changed num 46 description to read, “\overline{TA} assertion to rising edge ...” In Figure 46, changed \overline{TA} to reflect the rising edge of the clock. |
| 7.0 | 9/2004 | <ul style="list-style-type: none"> Added a tablefootnote to Table 6 DC Electrical Specifications about meeting the VIL Max of the I2C Standard Replaced the thermal characteristics in Table 4 by the ZQ package Add the new parts to the Ordering and Availability Chart in Table 34 Added the mechanical spec of the ZQ package in Figure 78 Removed all of the old revisions from Table 5 |
| 6.3 | 9/2003 | <ul style="list-style-type: none"> Added Section 11.2 on the Port C interrupt pins Nontechnical reformatting |
| 6.2 | 8/2003 | <ul style="list-style-type: none"> Changed B28a through B28d and B29d to show that TRLX can be 0 or 1 Changed reference documentation to reflect the Rev 2 MPC860 PowerQUICC Family Users Manual Nontechnical reformatting |
| 6.1 | 11/2002 | <ul style="list-style-type: none"> Corrected UTOPIA RXenb* and TXenb* timing values Changed incorrect usage of Vcc to Vdd Corrected dual port RAM to 8 Kbytes |
| 6 | 10/2002 | Added the MPC855T. Corrected Figure 26 on page -36 . |
| 5.1 | 11/2001 | Revised template format, removed references to MAC functionality, changed Table 7 B23 max value @ 66 MHz from 2ns to 8ns, added this revision history table |